## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10516625	MIYANO ET AL.	
Examiner	Art Unit	
Le, Hien	3662	

SEARCHED				
Class	Subclass	Date	Examiner	
Inventor's Name Search		12/8/2006	·	
Plus Search		12/8/2006		
NPL Search		12/11/2006		
Text Search		12/8/2006		
342	357.12,357.15,357.13,357.06,357.05	12/8/2006		
455	73	12/8/2006		
370	320	12/8/2006		
375	148,340	12/8/2006		
701	213-216	12/8/2006		

SEARCH NOTES					
Search Notes	Date	Examiner			

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

U.S. Patent and Trademark Office Part of Paper No. :